

Form PTO 1449
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LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Yuuichi HIRANO, et al.

FILING DATE

Herewith

3/31/04

GROUP

Not Assigned

2815

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
Q. H.	AA	5,373,170	12-1994	Pfiester et al.	257	69	
	AB	5,422,499	06-1995	Manning, Monte	257	67	
	AC	6,020,242	02-2000	Tsai et al.	438	279	
	AD	6,429,124	08-2002	Tang et al.	438	643	
Q. H.	AE	5,395,783	03/07/1995	R.C. Baumann, et al.	438	239	
	AF						
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	AM						
	AN						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
Q. H.	AO	6-188388	07/08/94	Japan (with English abstract)		X
	AP	5-235301	09/10/93	Japan (with English abstract)		X
	AQ	690 09 157	09/08/1994	Germany (with corr. EP 0 432 057		X
Q. H.	AR	0 432 057	06/12/1991	Europe		X
	AS					
	AT					
	AU					
	AV					

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

Q. H.	AW	Ross A. KOHLER, et al. "SEU CHARACTERIZATION OF HARDENED CMOS SRAMS USING STATISTICAL ANALYSIS OF FEEDBACK DELAY IN MEMORY CELLS", IEEE Transactions on Nuclear Science, Vol 36, No. 6, December 1989, pages 2318-2323.				
	AX					
	AY					
	AZ					

☐ Additional References sheet(s) attached

Examiner

Q. H.

Date Considered

9/27/04

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.